

MASSACHUSETTS INSTITUTE OF TECHNOLOGY
Department of Electrical Engineering and Computer Science

6.012 MICROELECTRONIC DEVICES AND CIRCUITS

Problem Set No. 2

Issued: September 16, 2009

Due: September 23, 2009

Reading Assignments:

- Lecture 3 (9/17/09) - Chap. 4 (4.2, 4.3), Chap. 6 (begin)
 Lecture 4 (9/22/09) - Chap. 6 (all), Chap. 7 (7.1, 7.2)
 Lecture 5 (9/24/09) - Chap. 5 (5.1)

Problem 1 - We say that we can approximate the minority carrier lifetime in Si as being infinite even though it is really several hundred milliseconds, because this is a long time compared to the time it takes a hole or an electron to drift or diffuse across a device to a contact or junction. To verify this statement consider the following two questions:

- a) With drift, the time it takes a carrier to go (transit) a distance d is: $\tau_{tr/Drift} = d/\mu E$.
- i) How long does it take an electron ($\mu_e = 1600 \text{ cm}^2/\text{V-s}$) to drift $10 \mu\text{m}$ in a field of 10 V/cm ?
 - ii) Repeat a) i) for a hole ($\mu_h = 600 \text{ cm}^2/\text{V-s}$).
 - iii) Compare your answers in a) i) and a) ii) to a lifetime of 100 ms. Is approximating this lifetime as "infinite" in this situation reasonable?
- b) With diffusion, the time it takes a carrier to transit a distance d is: $\tau_{tr/Diff} = d^2/2D$.
- i) How long does it take an electron ($D_e = 40 \text{ cm}^2/\text{s}$) to diffuse $10 \mu\text{m}$ in a concentration gradient of 10^{15} cm^{-3} per micron?
 - ii) Repeat b) i) for a hole ($D_h = 15 \text{ cm}^2/\text{s}$).
 - iii) Compare your answers in a) i) and a) ii) to a lifetime of 100 ms. Is approximating this lifetime as "infinite" in this situation reasonable?

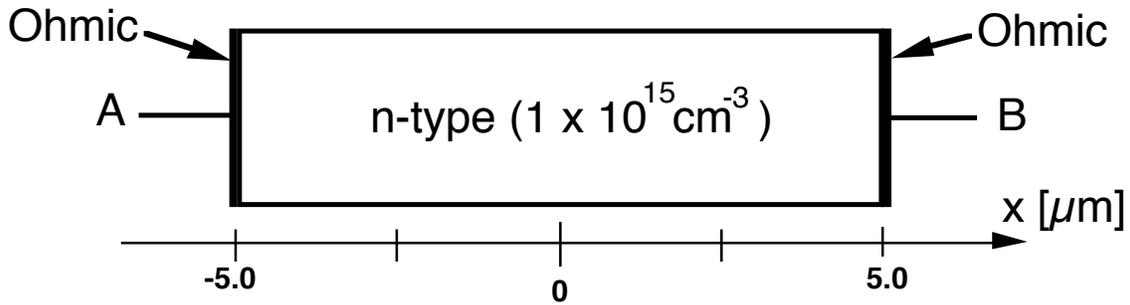
Problem 2 - Do Problem 3.9, Parts a thru d, in the course textbook.

Problem 3 - Two short problems:

- i) Do Problem 4.3 in the course textbook.
- ii) Do Problem 4.2 in the course textbook.

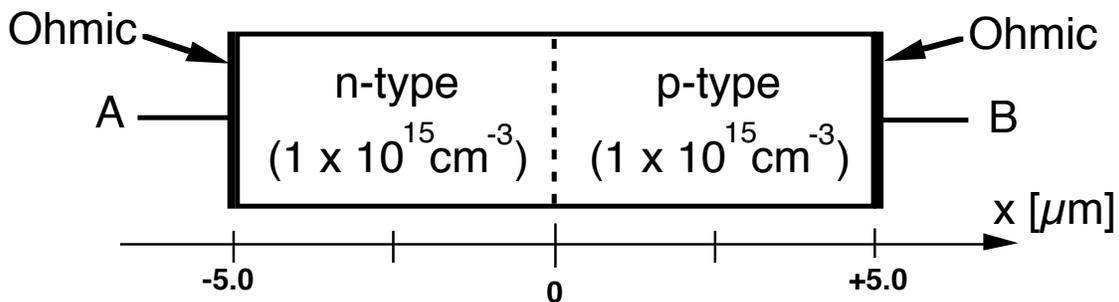
Problem 4 - The n-type silicon sample illustrated on the top of the next page is 10 microns (μm) long and has metal ohmic contacts, A and B, on either end. The net donor concentration is $1 \times 10^{15} \text{ cm}^{-3}$; the electron mobility, μ_{eV} is $1600 \text{ cm}^2/\text{V-s}$; and the hole mobility, μ_{hV} is $600 \text{ cm}^2/\text{V-s}$. The electrostatic potential of the metal relative to intrinsic silicon is 0.2V, and the intrinsic carrier concentration at room temperature is 10^{10} cm^{-3} .

Use the 60 mV rule to calculate the electrostatic potential, i.e. use $(kT/q) \ln 10 = 0.06 \text{ V}$.



- What are the thermal equilibrium (i.e., no light, $v_{AB} = 0$ V) hole and electron concentrations and electrostatic potential, ϕ_n , in this silicon?
- Sketch the electrostatic potential, $\phi(x)$, with $v_{AB} = 0$ V, going from the metal on the left, through the silicon, and into the metal on the right. Dimension your sketch; label any significant features.
- Assume now that $v_{AB} = 0.5$ V. Sketch the electrostatic potential, $\phi(x)$, with $v_{AB} = 0.5$ V, going from the metal on the left, through the silicon, and into the metal on the right (where you should assume the value of ϕ is unchanged, i.e. 0.2 V). Dimension your sketch and label any significant features, including $\phi(0)$.
- When $v_{AB} = 0.5$ V, what are the electron and hole drift current densities, J_e^{dr} and J_h^{dr} , respectively, at $x = 0$ μm

Next consider a sample similar to our original sample, except that it is doped p-type with a net acceptor concentration of $1 \times 10^{15} \text{ cm}^{-3}$ in the region from $x = 0$ μm to $x = +5$ μm as shown below. **Note:** This is a diode with the p-side to the right.



- Sketch the electrostatic potential, $\phi(x)$, going from the metal on the left, through the silicon, and into the metal on the right, with $v_{AB} = 0$ V. Dimension your sketch and label any significant features, including the value of $\phi(0)$.
- The diode is now reverse biased by $v_{AB} = 0.5$ V. Sketch the electrostatic potential, $\phi(x)$, now, going from the metal on the left, through the silicon, and into the metal on the right. Keep ϕ in the metal to the right of $x = 5$ μm at the value it had in Part f. Dimension your sketch and label any significant features, including the value of $\phi(0)$.

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